

# NTE74LS107 Integrated Circuit TTL – Dual J–K Negative Edge Triggered Flip–Flop with Clear

## **Description:**

The NTE74LS107 contains two independent negative–edge–triggered flip–flops in a 14–Lead plastic DIP type package. The J and K inputs must be stable one setup prior to the high–to–low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the  $\overline{Q}$  output high.

# Absolute Maximum Ratings: (Note 1)

Supply Voltage, V <sub>CC</sub>	. 7V
DC Input Voltage, V <sub>IN</sub>	. 7V
Operating Temperature Range, T <sub>A</sub> 0°C to +7	70°C
Storage Temperature Range, T <sub>stg</sub>	50°C

Note 1. Unless otherwise specified, all voltages are referenced to GND.

#### **Recommended Operating Conditions:**

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage	V <sub>CC</sub>	4.75	5.0	5.25	V
High-Level Input Voltage	V <sub>IH</sub>	2.0	-	-	V
Low-Level Input Voltage	V <sub>IL</sub>	-	-	0.8	V
High-Level Output Current	I <sub>OH</sub>	-	-	-0.4	mA
Low-Level Output Current	I <sub>OL</sub>	-	-	8	mA
Clock Frequency	f <sub>clock</sub>	0	-	30	MHz
Pulse Duration CLK High	t <sub>w</sub>	20	_	_	ns
CLR Low		25	_	-	ns
Setup Time before CLK↓ Data High or Low	t <sub>su</sub>	20	_	_	ns
CLR Inactive		25	-	-	ns
Hold Time Data after CLK↓	t <sub>h</sub>	20	-	-	ns
Operating Temperature Range	T <sub>A</sub>	0	-	+70	°C

#### Electrical Characteristics: (Note 2, Note 3)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Input Clamp Voltage	V <sub>IK</sub>	$V_{CC} = MIN, I_I = -18mA$	-	-	-1.5	V
High Level Output Voltage	V <sub>OH</sub>	$V_{CC}$ = MIN, $V_{IH}$ = 2V, $V_{IL}$ = MAX, $I_{OH}$ = -0.4mA	2.7	3.4	-	V
Low Level Output Voltage	V <sub>OL</sub>	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = MAX, I_{OL} = 4mA$	-	0.25	0.4	V
		$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = MAX, I_{OL} = 8mA$	-	0.35	0.5	V
Input Current J or K	I	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7V	_	_	0.1	mA
CLR			-	-	0.3	mA
CLK			-	-	0.4	mA
High Level Input Current J or K	IIH	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V	_	_	20	μA
CLR			-	-	60	μA
CLK			-	-	80	μA
Low Level Input Current J or K	IIL	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V	_	_	-0.4	mA
CLK or CLR			-	-	-0.8	mA
Short-Circuit Output Current	I <sub>OS</sub>	V <sub>CC</sub> = MAX, Note 4	-20	-	-100	mA
Supply Current	I <sub>CC</sub>	V <sub>CC</sub> = MAX, Note 5	-	4	6	mA

- Note 2. .For conditions shown as MIN or MAX, use the appropriate value specified under "Recommended Operation Conditions".
- Note 3. All typical values are at  $V_{CC} = 5V$ ,  $T_A = +25^{\circ}C$ .
- Note 4. For certain devices where state commutation can be caused by shorting an output to GND, an equivalent test may be performed with  $V_0 = 2.125V$  and the minimum and maximum limits reduced to one half of their stated values.
- Note 5. With all outputs open,  $I_{CC}$  is measured with the Q and  $\overline{Q}$  outputs high in turn. At the time of measurement, the clock input is grounded.

#### <u>Switching Characteristics</u>: ( $V_{CC} = 5V$ , $T_A = +25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Maximum Clock Frequency	t <sub>max</sub>	$R_L = 2k\Omega$ , $C_L = 15pF$	30	45	_	MHz
Propagation Delay Time (From CLR or CLK Input to Q or Q Output)	t <sub>PLH</sub> , t <sub>PHL</sub>		-	15	20	ns

Inputs			Outputs			
CLR	CLK	J	K	Q	Q	
L	Х	Х	Х	L	Н	
Н	$\downarrow$	L	L	Q <sub>0</sub>	$\overline{Q}_{0}$	
Н	$\downarrow$	Н	L	Н	L	
Н	$\downarrow$	L	Н	L	Н	
Н	$\downarrow$	Н	Н	Toggle		
Н	Н	Х	Х	Q <sub>0</sub>	$\overline{Q}_{0}$	

## Truth Table:

